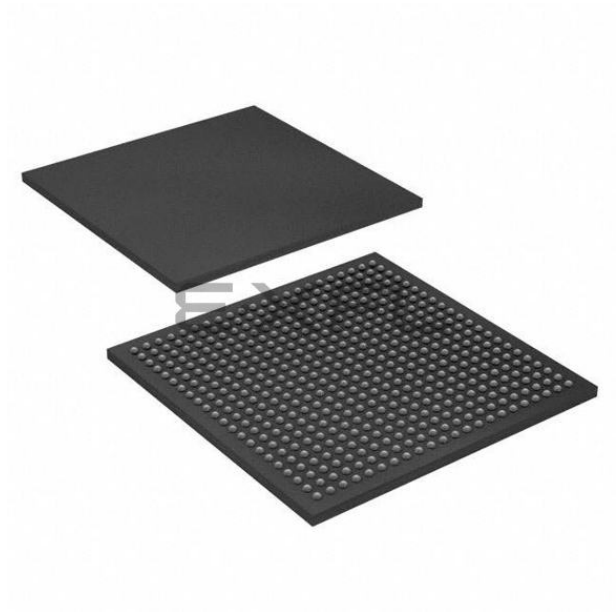

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	5831
Number of Logic Elements/Cells	74637
Total RAM Bits	3170304
Number of I/O	328
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	484-FBGA, CSPBGA
Supplier Device Package	484-CSPBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6slx75-3csg484c

Table 4: **DC Characteristics Over Recommended Operating Conditions**

Symbol	Description		Min	Typ	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)		0.8	–	–	V
V_{DRAUX}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)		2.0	–	–	V
I_{REF}	V_{REF} leakage current per pin for commercial (C) and industrial (I) devices		–10	–	10	µA
	V_{REF} leakage current per pin for expanded (Q) devices		–15	–	15	µA
I_L	Input or output leakage current per pin (sample-tested) for commercial (C) and industrial (I) devices		–10	–	10	µA
	Input or output leakage current per pin (sample-tested) for expanded (Q) devices		–15	–	15	µA
I_{HS}	Leakage current on pins during hot socketing with FPGA unpowered	All pins except PROGRAM_B, DONE, and JTAG pins when HSWAPEN = 1	–20	–	20	µA
		PROGRAM_B, DONE, and JTAG pins, or other pins when HSWAPEN = 0	$I_{HS} + I_{RPU}$			µA
C_{IN}[1]	Die input capacitance at the pad		–	–	10	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 3.3V or V_{CCAUX} = 3.3V		200	–	500	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 2.5V or V_{CCAUX} = 2.5V		120	–	350	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.8V		60	–	200	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.5V		40	–	150	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.2V		12	–	100	µA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = V_{CCO}, V_{CCAUX} = 3.3V		200	–	550	µA
	Pad pull-down (when selected) @ V_{IN} = V_{CCO}, V_{CCAUX} = 2.5V		140	–	400	µA
I_{BATT}[2]	Battery supply current		–	–	150	nA
R_{DT}[3]	Resistance of optional input differential termination circuit, V_{CCAUX} = 3.3V		–	100	–	Ω
R_{IN_TERM}[5]	Thevenin equivalent resistance of programmable input termination to V_{CCO} (UNTUNED_SPLIT_25) for commercial (C) and industrial (I) devices		23	25	55	Ω
	Thevenin equivalent resistance of programmable input termination to V_{CCO} (UNTUNED_SPLIT_25) for expanded (Q) devices		20	25	55	Ω
	Thevenin equivalent resistance of programmable input termination to V_{CCO} (UNTUNED_SPLIT_50) for commercial (C) and industrial (I) devices		39	50	72	Ω
	Thevenin equivalent resistance of programmable input termination to V_{CCO} (UNTUNED_SPLIT_50) for expanded (Q) devices		32	50	74	Ω
	Thevenin equivalent resistance of programmable input termination to V_{CCO} (UNTUNED_SPLIT_75) for commercial (C) and industrial (I) devices		56	75	109	Ω
	Thevenin equivalent resistance of programmable input termination to V_{CCO} (UNTUNED_SPLIT_75) for expanded (Q) devices		47	75	115	Ω
R_{OUT_TERM}	Thevenin equivalent resistance of programmable output termination (UNTUNED_25)		11	25	52	Ω
	Thevenin equivalent resistance of programmable output termination (UNTUNED_50)		21	50	96	Ω
	Thevenin equivalent resistance of programmable output termination (UNTUNED_75)		29	75	145	Ω

Notes:

1. The C_{IN} measurement represents the die capacitance at the pad, not including the package.
2. Maximum value specified for worst case process at 25°C. LX75, LX75T, LX100, LX100T, LX150, and LX150T only.
3. Refer to IBIS models for R_{DT} variation and for values at V_{CCAUX} = 2.5V. IBIS values for R_{DT} are valid for all temperature ranges.
4. V_{CCO2} is not required for data retention. The minimum V_{CCO2} for power-on reset and configuration is 1.65V.
5. Termination resistance to a V_{CCO}/2 level.

Table 5: **Typical Quiescent Supply Current *(Cont'd)***

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
I_{CCAUXQ}	Quiescent V_{CCAUX} supply current	LX4	2.5	2.5	2.5	2.5	mA
		LX9	2.5	2.5	2.5	2.5	mA
		LX16	3.0	3.0	3.0	3.0	mA
		LX25	4.0	4.0	4.0	4.0	mA
		LX25T	4.0	4.0	4.0	N/A	mA
		LX45	5.0	5.0	5.0	5.0	mA
		LX45T	5.0	5.0	5.0	N/A	mA
		LX75	7.0	7.0	7.0	7.0	mA
		LX75T	7.0	7.0	7.0	N/A	mA
		LX100	9.0	9.0	9.0	9.0	mA
		LX100T	9.0	9.0	9.0	N/A	mA
		LX150	12.0	12.0	12.0	12.0	mA
		LX150T	12.0	12.0	12.0	N/A	mA

Notes:

1. Typical values are specified at nominal voltage, 25°C junction temperatures (Tj). Industrial (I) grade devices have the same typical values as commercial (C) grade devices at 25°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. Nominal V_{CCINT} is 1.20V; use the XPE tool to calculate 1.23V values for the nominal V_{CCINT} of the extended performance range.
2. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
3. If differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools.

Table 6: **Power Supply Ramp Time**

Symbol	Description	Speed Grade	Ramp Time	Units
V_{CCINTR}	Internal supply voltage ramp time	-3, -3N, -2	0.20 to 50.0	ms
		-1L	0.20 to 40.0	ms
V_{CCO2}(1)	Output drivers bank 2 supply voltage ramp time	All	0.20 to 50.0	ms
V_{CCAUXR}	Auxiliary supply voltage ramp time	All	0.20 to 50.0	ms

Notes:

1. The minimum V_{CCO2} for power-on reset and configuration is 1.65V.
2. Spartan-6 FPGAs require a certain amount of supply current during power-on to insure proper device initialization. The actual current consumed depends on the power-on ramp rate of the power supply. Use the XPOWER Estimator (XPE) or XPOWER Analyzer (XPA) tools to estimate current drain on these supplies. Spartan-6 devices do not have a required power-on sequence.

SelectIO™ Interface DC Input and Output Levels

Table 7: **Recommended Operating Conditions for User I/Os Using Single-Ended Standards**

I/O Standard	V_{CCO} for Drivers[1]			V_{REF} for Inputs		
	V, Min	V, Nom	V, Max	V, Min	V, Nom	V, Max
LVTTL	3.0	3.3	3.45	V_{REF} is not used for these I/O standards		
LVCMOS33	3.0	3.3	3.45			
LVCMOS25	2.3	2.5	2.7			
LVCMOS18	1.65	1.8	1.95			
LVCMOS18_JEDEC	1.65	1.8	1.95			
LVCMOS15	1.4	1.5	1.6			
LVCMOS15_JEDEC	1.4	1.5	1.6			
LVCMOS12	1.1	1.2	1.3			
LVCMOS12_JEDEC	1.1	1.2	1.3			
PCI33_3[2]	3.0	3.3	3.45			
PCI66_3[2]	3.0	3.3	3.45			
I2C	2.7	3.0	3.45			
SMBUS	2.7	3.0	3.45			
SDIO	3.0	3.3	3.45			
MOBILE_DDR	1.7	1.8	1.9			
HSTL_I	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_II	1.4	1.5	1.6	0.68	0.75	0.9
HSTL_III	1.4	1.5	1.6	–	0.9	–
HSTL_I_18	1.7	1.8	1.9	0.8	0.9	1.1
HSTL_II_18	1.7	1.8	1.9	–	0.9	–
HSTL_III_18	1.7	1.8	1.9	–	1.1	–
SSTL3_I	3.0	3.3	3.45	1.3	1.5	1.7
SSTL3_II	3.0	3.3	3.45	1.3	1.5	1.7
SSTL2_I	2.3	2.5	2.7	1.13	1.25	1.38
SSTL2_II	2.3	2.5	2.7	1.13	1.25	1.38
SSTL18_I	1.7	1.8	1.9	0.833	0.9	0.969
SSTL18_II	1.7	1.8	1.9	0.833	0.9	0.969
SSTL15_II	1.425	1.5	1.575	0.69	0.75	0.81

Notes:

1. V_{CCO} range required when using I/O standard for an output. Also required for MOBILE_DDR, PCI33_3, LVCMOS18_JEDEC, LVCMOS15_JEDEC, and LVCMOS12_JEDEC inputs, and for LVCMOS25 inputs when V_{CCAUX} = 3.3V.
2. For PCI systems, the transmitter and receiver should have common supplies for V_{CCO}.

Table 21: **GTP Transceiver User Clock Switching Characteristics(1)**

Symbol	Description	Conditions	Speed Grade				Units
			-3	-3N	-2	-1L	
F_{TXOUT}	TXOUTCLK maximum frequency		320	320	270	N/A	MHz
F_{RXREC}	RXRECCLK maximum frequency		320	320	270	N/A	MHz
T_{RX}	RXUSRCLK maximum frequency		320	320	270	N/A	MHz
T_{RX2}	RXUSRCLK2 maximum frequency	1 byte interface	156.25	156.25	125	N/A	MHz
		2 byte interface	160	160	125	N/A	MHz
		4 byte interface	80	80	67.5	N/A	MHz
T_{TX}	TXUSRCLK maximum frequency		320	320	270	N/A	MHz
T_{TX2}	TXUSRCLK2 maximum frequency	1 byte interface	156.25	156.25	125	N/A	MHz
		2 byte interface	160	160	125	N/A	MHz
		4 byte interface	80	80	67.5	N/A	MHz

Notes:
1. Clocking must be implemented as described in UG386: *Spartan-6 FPGA GTP Transceivers User Guide*.

Table 22: **GTP Transceiver Transmitter Switching Characteristics**

Symbol	Description	Condition	Min	Typ	Max	Units
T_{RTX}	TX Rise time	20%–80%	–	140	–	ps
T_{FTX}	TX Fall time	80%–20%	–	120	–	ps
T_{LLSKEW}	TX lane-to-lane skew(1)		–	–	400	ps
$V_{TXOOBVDPP}$	Electrical idle amplitude		–	–	20	mV
$T_{TXOOBTRANSITION}$	Electrical idle transition time		–	–	50	ns
$T_{J3.125}$	Total Jitter(2)	3.125 Gb/s	–	–	0.35	UI
$D_{J3.125}$	Deterministic Jitter(2)		–	–	0.15	UI
$T_{J2.5}$	Total Jitter(2)	2.5 Gb/s	–	–	0.33	UI
$D_{J2.5}$	Deterministic Jitter(2)		–	–	0.15	UI
$T_{J1.62}$	Total Jitter(2)	1.62 Gb/s	–	–	0.20	UI
$D_{J1.62}$	Deterministic Jitter(2)		–	–	0.10	UI
$T_{J1.25}$	Total Jitter(2)	1.25 Gb/s	–	–	0.20	UI
$D_{J1.25}$	Deterministic Jitter(2)		–	–	0.10	UI
T_{J614}	Total Jitter(2)	614 Mb/s	–	–	0.10	UI
D_{J614}	Deterministic Jitter(2)		–	–	0.05	UI

Notes:
1. Using same REFCLK input with TXENPMAPHASEALIGN enabled for up to four consecutive GTP transceiver sites.
2. Using PLL_DIVSEL_FB = 2, INTDATAWIDTH = 1. These values are NOT intended for protocol specific compliance determinations.

Table 28: **IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L[1]	-3	-3N	-2	-1L[1]	-3	-3N	-2	-1L[1]	
LVCMOS33, Fast, 8 mA	1.34	1.46	1.59	1.82	2.07	2.21	2.41	3.03	2.07	2.21	2.41	3.03	ns
LVCMOS33, Fast, 12 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns
LVCMOS33, Fast, 16 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns
LVCMOS33, Fast, 24 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns
LVCMOS25, QUIETIO, 2 mA	0.82	0.94	1.07	1.31	4.81	4.95	5.15	5.79	4.81	4.95	5.15	5.79	ns
LVCMOS25, QUIETIO, 4 mA	0.82	0.94	1.07	1.31	3.70	3.84	4.04	4.66	3.70	3.84	4.04	4.66	ns
LVCMOS25, QUIETIO, 6 mA	0.82	0.94	1.07	1.31	3.46	3.60	3.80	4.38	3.46	3.60	3.80	4.38	ns
LVCMOS25, QUIETIO, 8 mA	0.82	0.94	1.07	1.31	3.20	3.34	3.54	4.12	3.20	3.34	3.54	4.12	ns
LVCMOS25, QUIETIO, 12 mA	0.82	0.94	1.07	1.31	2.83	2.97	3.17	3.75	2.83	2.97	3.17	3.75	ns
LVCMOS25, QUIETIO, 16 mA	0.82	0.94	1.07	1.31	2.64	2.78	2.98	3.64	2.64	2.78	2.98	3.64	ns
LVCMOS25, QUIETIO, 24 mA	0.82	0.94	1.07	1.31	2.45	2.59	2.79	3.42	2.45	2.59	2.79	3.42	ns
LVCMOS25, Slow, 2 mA	0.82	0.94	1.07	1.31	3.78	3.92	4.12	4.76	3.78	3.92	4.12	4.76	ns
LVCMOS25, Slow, 4 mA	0.82	0.94	1.07	1.31	2.79	2.93	3.13	3.73	2.79	2.93	3.13	3.73	ns
LVCMOS25, Slow, 6 mA	0.82	0.94	1.07	1.31	2.73	2.87	3.07	3.66	2.73	2.87	3.07	3.66	ns
LVCMOS25, Slow, 8 mA	0.82	0.94	1.07	1.31	2.48	2.62	2.82	3.42	2.48	2.62	2.82	3.42	ns
LVCMOS25, Slow, 12 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.95	2.01	2.15	2.35	2.95	ns
LVCMOS25, Slow, 16 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.95	2.01	2.15	2.35	2.95	ns
LVCMOS25, Slow, 24 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.94	2.01	2.15	2.35	2.94	ns
LVCMOS25, Fast, 2 mA	0.82	0.94	1.07	1.31	3.35	3.49	3.69	4.31	3.35	3.49	3.69	4.31	ns
LVCMOS25, Fast, 4 mA	0.82	0.94	1.07	1.31	2.25	2.39	2.59	3.22	2.25	2.39	2.59	3.22	ns
LVCMOS25, Fast, 6 mA	0.82	0.94	1.07	1.31	2.09	2.23	2.43	3.05	2.09	2.23	2.43	3.05	ns
LVCMOS25, Fast, 8 mA	0.82	0.94	1.07	1.31	2.02	2.16	2.36	2.98	2.02	2.16	2.36	2.98	ns
LVCMOS25, Fast, 12 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns
LVCMOS25, Fast, 16 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns
LVCMOS25, Fast, 24 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns
LVCMOS18, QUIETIO, 2 mA	1.18	1.30	1.43	2.04	5.92	6.06	6.26	6.80	5.92	6.06	6.26	6.80	ns
LVCMOS18, QUIETIO, 4 mA	1.18	1.30	1.43	2.04	4.74	4.88	5.08	5.63	4.74	4.88	5.08	5.63	ns
LVCMOS18, QUIETIO, 6 mA	1.18	1.30	1.43	2.04	4.05	4.19	4.39	4.96	4.05	4.19	4.39	4.96	ns
LVCMOS18, QUIETIO, 8 mA	1.18	1.30	1.43	2.04	3.71	3.85	4.05	4.63	3.71	3.85	4.05	4.63	ns
LVCMOS18, QUIETIO, 12 mA	1.18	1.30	1.43	2.04	3.35	3.49	3.69	4.27	3.35	3.49	3.69	4.27	ns
LVCMOS18, QUIETIO, 16 mA	1.18	1.30	1.43	2.04	3.20	3.34	3.54	4.14	3.20	3.34	3.54	4.14	ns
LVCMOS18, QUIETIO, 24 mA	1.18	1.30	1.43	2.04	2.96	3.10	3.30	3.98	2.96	3.10	3.30	3.98	ns
LVCMOS18, Slow, 2 mA	1.18	1.30	1.43	2.04	4.62	4.76	4.96	5.54	4.62	4.76	4.96	5.54	ns
LVCMOS18, Slow, 4 mA	1.18	1.30	1.43	2.04	3.69	3.83	4.03	4.60	3.69	3.83	4.03	4.60	ns
LVCMOS18, Slow, 6 mA	1.18	1.30	1.43	2.04	3.00	3.14	3.34	3.94	3.00	3.14	3.34	3.94	ns
LVCMOS18, Slow, 8 mA	1.18	1.30	1.43	2.04	2.19	2.33	2.53	3.17	2.19	2.33	2.53	3.17	ns
LVCMOS18, Slow, 12 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVCMOS18, Slow, 16 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns

Table 28: **IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L[1]	-3	-3N	-2	-1L[1]	-3	-3N	-2	-1L[1]	
LVCMOS18, Slow, 24 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVCMOS18, Fast, 2 mA	1.18	1.30	1.43	2.04	3.59	3.73	3.93	4.53	3.59	3.73	3.93	4.53	ns
LVCMOS18, Fast, 4 mA	1.18	1.30	1.43	2.04	2.39	2.53	2.73	3.35	2.39	2.53	2.73	3.35	ns
LVCMOS18, Fast, 6 mA	1.18	1.30	1.43	2.04	1.88	2.02	2.22	2.84	1.88	2.02	2.22	2.84	ns
LVCMOS18, Fast, 8 mA	1.18	1.30	1.43	2.04	1.81	1.95	2.15	2.77	1.81	1.95	2.15	2.77	ns
LVCMOS18, Fast, 12 mA	1.18	1.30	1.43	2.04	1.71	1.85	2.05	2.67	1.71	1.85	2.05	2.67	ns
LVCMOS18, Fast, 16 mA	1.18	1.30	1.43	2.04	1.71	1.85	2.05	2.67	1.71	1.85	2.05	2.67	ns
LVCMOS18, Fast, 24 mA	1.18	1.30	1.43	2.04	1.71	1.85	2.05	2.67	1.71	1.85	2.05	2.67	ns
LVCMOS18_JEDEC, QUIETIO, 2 mA	0.94	1.06	1.19	1.41	5.91	6.05	6.25	6.79	5.91	6.05	6.25	6.79	ns
LVCMOS18_JEDEC, QUIETIO, 4 mA	0.94	1.06	1.19	1.41	4.75	4.89	5.09	5.64	4.75	4.89	5.09	5.64	ns
LVCMOS18_JEDEC, QUIETIO, 6 mA	0.94	1.06	1.19	1.41	4.04	4.18	4.38	4.96	4.04	4.18	4.38	4.96	ns
LVCMOS18_JEDEC, QUIETIO, 8 mA	0.94	1.06	1.19	1.41	3.71	3.85	4.05	4.62	3.71	3.85	4.05	4.62	ns
LVCMOS18_JEDEC, QUIETIO, 12 mA	0.94	1.06	1.19	1.41	3.35	3.49	3.69	4.28	3.35	3.49	3.69	4.28	ns
LVCMOS18_JEDEC, QUIETIO, 16 mA	0.94	1.06	1.19	1.41	3.20	3.34	3.54	4.13	3.20	3.34	3.54	4.13	ns
LVCMOS18_JEDEC, QUIETIO, 24 mA	0.94	1.06	1.19	1.41	2.96	3.10	3.30	3.98	2.96	3.10	3.30	3.98	ns
LVCMOS18_JEDEC, Slow, 2 mA	0.94	1.06	1.19	1.41	4.59	4.73	4.93	5.54	4.59	4.73	4.93	5.54	ns
LVCMOS18_JEDEC, Slow, 4 mA	0.94	1.06	1.19	1.41	3.69	3.83	4.03	4.60	3.69	3.83	4.03	4.60	ns
LVCMOS18_JEDEC, Slow, 6 mA	0.94	1.06	1.19	1.41	3.00	3.14	3.34	3.94	3.00	3.14	3.34	3.94	ns
LVCMOS18_JEDEC, Slow, 8 mA	0.94	1.06	1.19	1.41	2.19	2.33	2.53	3.18	2.19	2.33	2.53	3.18	ns
LVCMOS18_JEDEC, Slow, 12 mA	0.94	1.06	1.19	1.41	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVCMOS18_JEDEC, Slow, 16 mA	0.94	1.06	1.19	1.41	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVCMOS18_JEDEC, Slow, 24 mA	0.94	1.06	1.19	1.41	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVCMOS18_JEDEC, Fast, 2 mA	0.94	1.06	1.19	1.41	3.57	3.71	3.91	4.52	3.57	3.71	3.91	4.52	ns
LVCMOS18_JEDEC, Fast, 4 mA	0.94	1.06	1.19	1.41	2.39	2.53	2.73	3.35	2.39	2.53	2.73	3.35	ns
LVCMOS18_JEDEC, Fast, 6 mA	0.94	1.06	1.19	1.41	1.88	2.02	2.22	2.84	1.88	2.02	2.22	2.84	ns
LVCMOS18_JEDEC, Fast, 8 mA	0.94	1.06	1.19	1.41	1.80	1.94	2.14	2.76	1.80	1.94	2.14	2.76	ns
LVCMOS18_JEDEC, Fast, 12 mA	0.94	1.06	1.19	1.41	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns
LVCMOS18_JEDEC, Fast, 16 mA	0.94	1.06	1.19	1.41	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns
LVCMOS18_JEDEC, Fast, 24 mA	0.94	1.06	1.19	1.41	1.72	1.86	2.06	2.68	1.72	1.86	2.06	2.68	ns
LVCMOS15, QUIETIO, 2 mA	0.98	1.10	1.23	1.79	5.47	5.61	5.81	6.38	5.47	5.61	5.81	6.38	ns
LVCMOS15, QUIETIO, 4 mA	0.98	1.10	1.23	1.79	4.61	4.75	4.95	5.51	4.61	4.75	4.95	5.51	ns
LVCMOS15, QUIETIO, 6 mA	0.98	1.10	1.23	1.79	4.07	4.21	4.41	4.97	4.07	4.21	4.41	4.97	ns
LVCMOS15, QUIETIO, 8 mA	0.98	1.10	1.23	1.79	3.91	4.05	4.25	4.81	3.91	4.05	4.25	4.81	ns
LVCMOS15, QUIETIO, 12 mA	0.98	1.10	1.23	1.79	3.53	3.67	3.87	4.51	3.53	3.67	3.87	4.51	ns
LVCMOS15, QUIETIO, 16 mA	0.98	1.10	1.23	1.79	3.32	3.46	3.66	4.31	3.32	3.46	3.66	4.31	ns
LVCMOS15, Slow, 2 mA	0.98	1.10	1.23	1.79	4.18	4.32	4.52	5.11	4.18	4.32	4.52	5.11	ns
LVCMOS15, Slow, 4 mA	0.98	1.10	1.23	1.79	3.42	3.56	3.76	4.34	3.42	3.56	3.76	4.34	ns
LVCMOS15, Slow, 6 mA	0.98	1.10	1.23	1.79	2.29	2.43	2.63	3.24	2.29	2.43	2.63	3.24	ns

Table 29: **IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices[1] *(Cont'd)***

I/O Standard	T_{IOPI}		T_{IOOP}		T_{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
LVCMOS18, QUIETIO, 16 mA	1.25	1.43	3.34	3.54	3.34	3.54	ns
LVCMOS18, QUIETIO, 24 mA	1.25	1.43	3.18	3.38	3.18	3.38	ns
LVCMOS18, Slow, 2 mA	1.25	1.43	4.79	4.99	4.79	4.99	ns
LVCMOS18, Slow, 4 mA	1.25	1.43	3.84	4.04	3.84	4.04	ns
LVCMOS18, Slow, 6 mA	1.25	1.43	3.17	3.37	3.17	3.37	ns
LVCMOS18, Slow, 8 mA	1.25	1.43	2.37	2.57	2.37	2.57	ns
LVCMOS18, Slow, 12 mA	1.25	1.43	2.13	2.33	2.13	2.33	ns
LVCMOS18, Slow, 16 mA	1.25	1.43	2.13	2.33	2.13	2.33	ns
LVCMOS18, Slow, 24 mA	1.25	1.43	2.13	2.33	2.13	2.33	ns
LVCMOS18, Fast, 2 mA	1.25	1.43	3.78	3.98	3.78	3.98	ns
LVCMOS18, Fast, 4 mA	1.25	1.43	2.54	2.74	2.54	2.74	ns
LVCMOS18, Fast, 6 mA	1.25	1.43	2.02	2.22	2.02	2.22	ns
LVCMOS18, Fast, 8 mA	1.25	1.43	1.95	2.15	1.95	2.15	ns
LVCMOS18, Fast, 12 mA	1.25	1.43	1.85	2.05	1.85	2.05	ns
LVCMOS18, Fast, 16 mA	1.25	1.43	1.85	2.05	1.85	2.05	ns
LVCMOS18, Fast, 24 mA	1.25	1.43	1.85	2.05	1.85	2.05	ns
LVCMOS18_JEDEC, QUIETIO, 2 mA	1.01	1.19	6.09	6.29	6.09	6.29	ns
LVCMOS18_JEDEC, QUIETIO, 4 mA	1.01	1.19	4.89	5.09	4.89	5.09	ns
LVCMOS18_JEDEC, QUIETIO, 6 mA	1.01	1.19	4.20	4.40	4.20	4.40	ns
LVCMOS18_JEDEC, QUIETIO, 8 mA	1.01	1.19	3.87	4.07	3.87	4.07	ns
LVCMOS18_JEDEC, QUIETIO, 12 mA	1.01	1.19	3.49	3.69	3.49	3.69	ns
LVCMOS18_JEDEC, QUIETIO, 16 mA	1.01	1.19	3.34	3.54	3.34	3.54	ns
LVCMOS18_JEDEC, QUIETIO, 24 mA	1.01	1.19	3.17	3.37	3.17	3.37	ns
LVCMOS18_JEDEC, Slow, 2 mA	1.01	1.19	4.79	4.99	4.79	4.99	ns
LVCMOS18_JEDEC, Slow, 4 mA	1.01	1.19	3.84	4.04	3.84	4.04	ns
LVCMOS18_JEDEC, Slow, 6 mA	1.01	1.19	3.18	3.38	3.18	3.38	ns
LVCMOS18_JEDEC, Slow, 8 mA	1.01	1.19	2.37	2.57	2.37	2.57	ns
LVCMOS18_JEDEC, Slow, 12 mA	1.01	1.19	2.13	2.33	2.13	2.33	ns
LVCMOS18_JEDEC, Slow, 16 mA	1.01	1.19	2.13	2.33	2.13	2.33	ns
LVCMOS18_JEDEC, Slow, 24 mA	1.01	1.19	2.13	2.33	2.13	2.33	ns
LVCMOS18_JEDEC, Fast, 2 mA	1.01	1.19	3.75	3.95	3.75	3.95	ns
LVCMOS18_JEDEC, Fast, 4 mA	1.01	1.19	2.54	2.74	2.54	2.74	ns
LVCMOS18_JEDEC, Fast, 6 mA	1.01	1.19	2.02	2.22	2.02	2.22	ns
LVCMOS18_JEDEC, Fast, 8 mA	1.01	1.19	1.94	2.14	1.94	2.14	ns
LVCMOS18_JEDEC, Fast, 12 mA	1.01	1.19	1.86	2.06	1.86	2.06	ns
LVCMOS18_JEDEC, Fast, 16 mA	1.01	1.19	1.86	2.06	1.86	2.06	ns
LVCMOS18_JEDEC, Fast, 24 mA	1.01	1.19	1.86	2.06	1.86	2.06	ns

I/O Standard Measurement Methodology

Input Delay Measurements

Table 31 shows the test setup parameters used for measuring input delay.

Table 31: **Input Delay Measurement Methodology**

Description	I/O Standard Attribute	V_L[1]	V_H[1]	V_{MEAS}[3][4]	V_{REF}[2][4]
LVTTL (Low-Voltage Transistor-Transistor Logic)	LVTTL	0	3.0	1.4	–
LVCMOS (Low-Voltage CMOS), 3.3V	LVCMOS33	0	3.3	1.65	–
LVCMOS, 2.5V	LVCMOS25	0	2.5	1.25	–
LVCMOS, 1.8V	LVCMOS18	0	1.8	0.9	–
LVCMOS, 1.5V	LVCMOS15	0	1.5	0.75	–
LVCMOS, 1.2V	LVCMOS12	0	1.2	0.6	–
PCI (Peripheral Component Interface), 33 MHz and 66 MHz, 3.3V	PCI33_3, PCI66_3	Per PCI Specification			–
HSTL (High-Speed Transceiver Logic), Class I & II	HSTL_I, HSTL_II	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.75
HSTL, Class III	HSTL_III	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.90
HSTL, Class I & II, 1.8V	HSTL_I_18, HSTL_II_18	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.90
HSTL, Class III 1.8V	HSTL_III_18	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	1.1
SSTL (Stub Terminated Transceiver Logic), Class I & II, 3.3V	SSTL3_I, SSTL3_II	V_{REF} – 0.75	V_{REF} + 0.75	V_{REF}	1.5
SSTL, Class I & II, 2.5V	SSTL2_I, SSTL2_II	V_{REF} – 0.75	V_{REF} + 0.75	V_{REF}	1.25
SSTL, Class I & II, 1.8V	SSTL18_I, SSTL18_II	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.90
SSTL, Class II, 1.5V	SSTL15_II	V_{REF} – 0.2	V_{REF} + 0.2	V_{REF}	0.75
LVDS (Low-Voltage Differential Signaling), 2.5V & 3.3V	LVDS_25, LVDS_33	1.25 – 0.125	1.25 + 0.125	0[5]	–
LVPECL (Low-Voltage Positive Emitter-Coupled Logic), 2.5V & 3.3V	LVPECL_25, LVPECL_33	1.2 – 0.3	1.2 + 0.3	0[5]	–
BLVDS (Bus LVDS), 2.5V	BLVDS_25	1.3 – 0.125	1.3 + 0.125	0[5]	–
Mini-LVDS, 2.5V & 3.3V	MINI_LVDS_25, MINI_LVDS_33	1.2 – 0.125	1.2 + 0.125	0[5]	–
RSDS (Reduced Swing Differential Signaling), 2.5V & 3.3V	RSDS_25, RSDS_33	1.2 – 0.1	1.2 + 0.1	0[5]	–
TMDS (Transition Minimized Differential Signaling), 3.3V	TMDS_33	3.0 – 0.1	3.0 + 0.1	0[5]	–
PPDS (Point-to-Point Differential Signaling, 2.5V & 3.3V	PPDS_25, PPDS_33	1.25 – 0.1	1.25 + 0.1	0[5]	–

Notes:
1. Input waveform switches between V_L and V_H.
2. Measurements are made at typical, minimum, and maximum V_{REF} values. Reported delays reflect worst case of these measurements. V_{REF} values listed are typical.
3. Input voltage level from which measurement starts.
4. This is an input voltage reference that bears no relation to the V_{REF} / V_{MEAS} parameters found in IBIS models and/or noted in Figure 4.
5. The value given is the differential input voltage.

Output Delay Measurements

Output delays are measured using a Tektronix P6245 TDS500/600 probe (< 1 pF) across approximately 4" of FR4 microstrip trace. Standard termination was used for all testing. The propagation delay of the 4" trace is characterized separately and subtracted from the final measurement, and is therefore not included in the generalized test setups shown in Figure 4 and Figure 5.

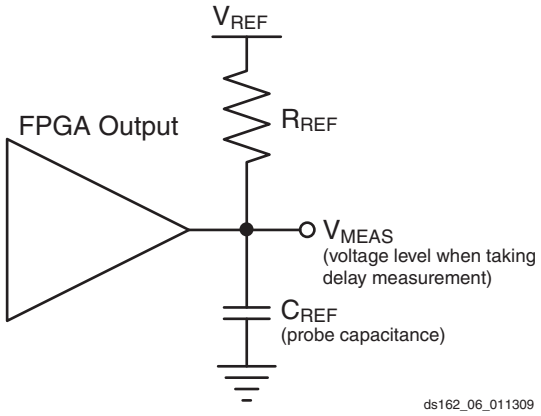

Figure 4: **Single-Ended Test Setup**

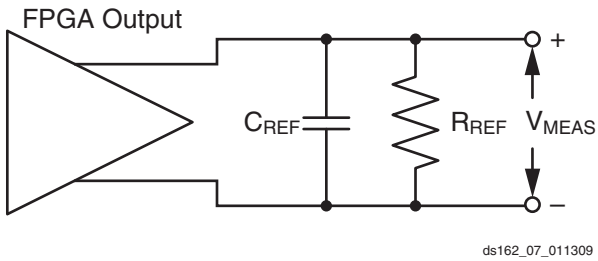

Figure 5: **Differential Test Setup**

Measurements and test conditions are reflected in the IBIS models except where the IBIS format precludes it. Parameters V_{REF}, R_{REF}, C_{REF}, and V_{MEAS} fully describe the test conditions for each I/O standard. The most accurate prediction of propagation delay in any given application can be obtained through IBIS simulation, using the following method:

1. Simulate the output driver of choice into the generalized test setup, using values from Table 32.
2. Record the time to V_{MEAS}.
3. Simulate the output driver of choice into the actual PCB trace and load, using the appropriate IBIS model or capacitance value to represent the load.
4. Record the time to V_{MEAS}.
5. Compare the results of steps 2 and 4. The increase or decrease in delay yields the actual propagation delay of the PCB trace.

Table 32: **Output Delay Measurement Methodology**

Description	I/O Standard Attribute	R_{REF} (Ω)	C_{REF} (1) (pF)	V_{MEAS} (V)	V_{REF} (V)
LVTTL (Low-Voltage Transistor-Transistor Logic)	LVTTL (all)	1M	0	1.4	0
LVCMOS (Low-Voltage CMOS), 3.3V	LVCMOS33	1M	0	1.65	0
LVCMOS, 2.5V	LVCMOS25	1M	0	1.25	0
LVCMOS, 1.8V	LVCMOS18	1M	0	0.9	0
LVCMOS, 1.5V	LVCMOS15	1M	0	0.75	0
LVCMOS, 1.2V	LVCMOS12	1M	0	0.6	0
PCI (Peripheral Component Interface) 33 MHz and 66 MHz, 3.3V	PCI33_3, PCI66_3 (rising edge)	25	10 (2)	0.94	0
	PCI33_3, PCI66_3 (falling edge)	25	10 (2)	2.03	3.3
HSTL (High-Speed Transceiver Logic), Class I	HSTL_I	50	0	V_{REF}	0.75
HSTL, Class II	HSTL_II	25	0	V_{REF}	0.75
HSTL, Class III	HSTL_III	50	0	0.9	1.5
HSTL, Class I, 1.8V	HSTL_I_18	50	0	V_{REF}	0.9
HSTL, Class II, 1.8V	HSTL_II_18	25	0	V_{REF}	0.9
HSTL, Class III, 1.8V	HSTL_III_18	50	0	1.1	1.8
SSTL (Stub Series Terminated Logic), Class I, 1.8V	SSTL18_I	50	0	V_{REF}	0.9
SSTL, Class II, 1.8V	SSTL18_II	25	0	V_{REF}	0.9
SSTL, Class I, 2.5V	SSTL2_I	50	0	V_{REF}	1.25

Table 32: **Output Delay Measurement Methodology *(Cont'd)***

Description	I/O Standard Attribute	R_{REF} (Ω)	C_{REF}[1] (pF)	V_{MEAS} (V)	V_{REF} (V)
SSTL, Class II, 2.5V	SSTL2_II	25	0	V_{REF}	1.25
SSTL, Class II, 1.5V	SSTL15_II	25	0	V_{REF}	0.75
LVDS (Low-Voltage Differential Signaling), 2.5V & 3.3V	LVDS_25, LVDS_33	100	0	0[3]	–
BLVDS (Bus LVDS), 2.5V	BLVDS_25	Note 4	0	0[3]	–
Mini-LVDS, 2.5V & 3.3V	MINI_LVDS_25, MINI_LVDS_33	100	0	0[3]	–
RSDS (Reduced Swing Differential Signaling), 2.5V & 3.3V	RSDS_25, RSDS_33	100	0	0[3]	–
TMDS (Transition Minimized Differential Signaling), 3.3V	TMDS_33	Note 5	0	0[3]	–
PPDS (Point-to-Point Differential Signaling, 2.5V & 3.3V	PPDS_25, PPDS_33	100	0	0[3]	–

Notes:
1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. Per PCI specifications.
3. The value given is the differential output voltage.
4. See the *BLVDS Output Termination* section in UG381, *Spartan-6 FPGA SelectIO Resources User Guide*.
5. See the *TMDS_33 Termination* section in UG381, *Spartan-6 FPGA SelectIO Resources User Guide*.

Simultaneously Switching Outputs

Due to package electrical parasitics, a given package supports a limited number of simultaneous switching outputs (SSOs) when using fast, high-drive outputs. Table 33 and Table 34 provide guidelines for the recommended maximum allowable number of SSOs. These guidelines describe the maximum number of user I/O pins of an output signal standard that should simultaneously switch in the same direction, while maintaining a safe level of switching noise for that particular signal standard. Meeting these guidelines for the stated test conditions ensures that the FPGA operates free from the adverse effects of GND and power bounce.

For each device/package combination, Table 33 provides the number of equivalent V_{CCO}/GND pairs per bank. For each output signal standard and drive strength, Table 34 recommends the maximum number of SSOs, switching in the same direction, allowed per V_{CCO}/GND pair within an I/O bank. The guidelines are categorized by package style, slew rate, and output drive current. The number of SSOs are also specified by I/O bank. Multiply the appropriate numbers from each table to calculate the maximum number of SSOs allowed within an I/O bank. The guidelines assume that all pins within a bank use the same I/O standard. Exceeding these SSO guidelines can result in increased power or GND bounce, degraded signal integrity, or increased system jitter. For a given I/O standard, if the SSO limit per pair in Table 34 is greater than the maximum I/O per pair in Table 33, then there is no SSO limit for the exclusive use of that I/O standard.

The recommended maximum SSO values assume that the FPGA is soldered on a printed circuit board and that the board uses sound design practices. Due to the additional inductance introduced by the socket, the SSO values do not apply for FPGAs mounted in sockets. The SSO values assume that the V_{CCAUX} is powered at 3.3V. Setting V_{CCAUX} to 2.5V provides better SSO characteristics. For more detail, see UG381: *Spartan-6 FPGA SelectIO Resources User Guide*.

Table 34: **SSO Limit per V_{CCO}/GND Pair *(Cont'd)***

V_{CCO}	I/O Standard	Drive	Slew	SSO Limit per V_{CCO}/GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
1.5V	LVCMOS15, LVCMOS15_JEDEC	2	Fast	33	40	33	41
			Slow	57	62	57	56
			QuietIO	70	67	70	66
		4	Fast	19	21	19	21
			Slow	30	30	30	24
			QuietIO	38	33	38	30
		6	Fast	14	16	14	16
			Slow	18	19	18	17
			QuietIO	27	24	27	21
		8	Fast	11	13	11	12
			Slow	16	16	16	14
			QuietIO	23	20	23	17
		12	Fast	N/A	5	N/A	4
			Slow	N/A	8	N/A	5
			QuietIO	N/A	10	N/A	9
		16	Fast	N/A	5	N/A	4
			Slow	N/A	8	N/A	8
			QuietIO	N/A	10	N/A	9
	HSTL_I			9	10	9	10
	HSTL_II			N/A	5	N/A	6
	HSTL_III			7	9	7	9
	DIFF_HSTL_I			27	30	27	30
	DIFF_HSTL_II			N/A	15	N/A	18
	DIFF_HSTL_III			21	27	21	27
	SSTL_15_II (3)			N/A	5	N/A	4
	DIFF_SSTL_15_II (3)			N/A	15	N/A	12

Table 34: **SSO Limit per V_{CCO}/GND Pair *(Cont'd)***

V_{CCO}	I/O Standard	Drive	Slew	SSO Limit per V_{CCO}/GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
3.3V	LVCMOS33	2	Fast	42	46	42	44
			Slow	50	55	50	49
			QuietIO	60	68	60	60
		4	Fast	21	27	21	25
			Slow	32	37	32	32
			QuietIO	39	42	39	37
		6	Fast	14	19	14	17
			Slow	19	25	19	22
			QuietIO	29	30	29	25
		8	Fast	11	15	11	14
			Slow	15	20	15	18
			QuietIO	25	24	25	20
		12	Fast	1	3	1	1
			Slow	2	5	2	2
			QuietIO	4	9	4	7
		16	Fast	1	2	1	1
			Slow	1	5	1	1
			QuietIO	3	10	3	8
		24	Fast	1	2	1	1
			Slow	2	5	2	1
			QuietIO	7	9	7	7

Table 34: **SSO Limit per V_{CCO}/GND Pair *(Cont'd)***

V_{CCO}	I/O Standard	Drive	Slew	SSO Limit per V_{CCO}/GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
3.3V	LVTTL	2	Fast	53	65	53	62
			Slow	70	80	70	73
			QuietIO	79	89	79	91
		4	Fast	23	30	23	27
			Slow	34	41	34	37
			QuietIO	44	49	44	46
		6	Fast	16	21	16	20
			Slow	21	28	21	25
			QuietIO	34	39	34	34
		8	Fast	12	16	12	15
			Slow	16	22	16	19
			QuietIO	27	28	27	24
		12	Fast	1	3	1	1
			Slow	2	5	2	4
			QuietIO	2	10	2	8
		16	Fast	1	3	1	1
			Slow	1	7	1	2
			QuietIO	3	11	3	8
		24	Fast	1	2	1	1
			Slow	2	5	2	2
			QuietIO	8	9	8	8
	PCI33_3			18	19	18	19
	PCI66_3			18	19	18	19
	SSTL_3_I			5	8	5	8
	SSTL_3_II			3	5	3	3
	DIFF_SSTL_3_I			15	24	15	24
	DIFF_SSTL_3_II			9	15	9	9
	SDIO			17	18	17	15

Input/Output Logic Switching Characteristics

Table 35: **ILOGIC2 Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold						
T_{ICE0CK}/T_{ICKCE0}	CE0 pin Setup/Hold with respect to CLK	0.56/ –0.30	0.56/ –0.25	0.79/ –0.22	1.21/ –0.52	ns
T_{ISRCK}/T_{ICKSR}	SR pin Setup/Hold with respect to CLK	0.74/ –0.23	0.74/ –0.22	0.98/ –0.20	1.31/ –0.45	ns
T_{IDOCK}/T_{IOCKD}	D pin Setup/Hold with respect to CLK without Delay	1.19/ –0.83	1.36/ –0.83	1.73/ –0.83	2.18/ –1.77	ns
T_{IDOCKD}/T_{IOCKDD}	DDLY pin Setup/Hold with respect to CLK (using IODELAY2)	0.31/ 0.00	0.47/ 0.00	0.54/ 0.00	0.63/ –0.39	ns
Combinatorial						
T_{IDI}	D pin to O pin propagation delay, no Delay	0.95	1.28	1.53	2.25	ns
T_{IDID}	DDLY pin to O pin propagation delay (using IODELAY2)	0.23	0.39	0.44	0.74	ns
Sequential Delays						
T_{IDLO}	D pin to Q pin using flip-flop as a latch without Delay	1.56	1.86	2.39	3.49	ns
T_{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY2)	0.68	0.97	1.20	1.94	ns
T_{ICKQ}	CLK to Q outputs for XC devices	1.03	1.24	1.43	2.11	ns
	CLK to Q outputs for XA and XQ devices	1.38	N/A	1.78	2.11	ns
$T_{RQ\_ILOGIC2}$	SR pin to Q outputs	1.81	1.81	2.50	3.05	ns

Table 36: **OLOGIC2 Switching Characteristics**

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold						
T_{ODCK}/T_{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.81/ –0.05	0.86/ –0.05	1.18/ 0.00	1.73/ –0.27	ns
T_{OOCECK}/T_{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.75/ –0.10	0.75/ –0.10	1.01/ –0.05	1.66/ –0.23	ns
T_{OSRCK}/T_{OCKSR}	SR pin Setup/Hold with respect to CLK	0.70/ –0.28	0.79/ –0.28	1.03/ –0.23	1.39/ –0.47	ns
T_{OTCK}/T_{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.24/ –0.08	0.56/ –0.06	0.83/ –0.01	0.99/ –0.19	ns
T_{OTCECK}/T_{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.58/ –0.06	0.72/ –0.06	1.18/ –0.01	1.51/ –0.13	ns
Sequential Delays						
T_{OCKQ}	CLK to OQ/TQ out for XC devices	0.48	0.51	0.74	0.74	ns
	CLK to OQ/TQ out for XA and XQ devices	0.85	N/A	1.16	0.74	ns
$T_{RQ\_OLOGIC2}$	SR pin to OQ/TQ out	1.81	1.81	2.50	3.05	ns

DSP48A1 Switching Characteristics

Table 44: **DSP48A1 Switching Characteristics**

Symbol	Description	Pre-adder	Multiplier	Post-adder	Speed Grade				Units
					-3	-3N	-2	-1L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock									
$T_{DSPDCK\_A\_A1REG}$/ $T_{DSPCKD\_A\_A1REG}$	A input to A1 register CLK	N/A	N/A	N/A	0.15/ 0.09	0.17/ 0.09	0.17/ 0.09	0.32/ 0.09	ns
$T_{DSPDCK\_D\_B1REG}$/ $T_{DSPCKD\_D\_B1REG}$	D input to B1 register CLK	Yes	N/A	N/A	1.90/ –0.07	1.95/ –0.07	1.95/ –0.07	2.82/ –0.07	ns
$T_{DSPDCK\_C\_CREG}$/ $T_{DSPCKD\_C\_CREG}$	C input to C register CLK for XC devices	N/A	N/A	N/A	0.11/ 0.15	0.13/ 0.15	0.13/ 0.15	0.24/ 0.09	ns
	C input to C register CLK for XA and XQ devices				0.11/ 0.19	N/A	0.13/ 0.23	0.24/ 0.09	
$T_{DSPDCK\_D\_DREG}$/ $T_{DSPCKD\_D\_DREG}$	D input to D register CLK for XC devices	N/A	N/A	N/A	0.09/ 0.15	0.10/ 0.15	0.10/ 0.15	0.19/ 0.12	ns
	D input to D register CLK for XA and XQ devices				0.09/ 0.23	N/A	0.10/ 0.27	0.19/ 0.12	
$T_{DSPDCK\_OPMODE\_B1REG}$/ $T_{DSPCKD\_OPMODE\_B1REG}$	OPMODE input to B1 register CLK	Yes	N/A	N/A	1.97/ 0.01	2.00/ 0.01	2.00/ 0.01	2.85/ 0.01	ns
$T_{DSPDCK\_OPMODE\_OPMODEREG}$/ $T_{DSPCKD\_OPMODE\_OPMODEREG}$	OPMODE input to OPMODE register CLK for XC devices	N/A	N/A	N/A	0.18/ 0.12	0.21/ 0.12	0.21/ 0.12	0.40/ 0.12	ns
	OPMODE input to OPMODE register CLK for XA and XQ devices				0.18/ 0.16	N/A	0.21/ 0.22	0.40/ 0.12	
Setup and Hold Times of Data Pins to the Pipeline Register Clock									
$T_{DSPDCK\_A\_MREG}$/ $T_{DSPCKD\_A\_MREG}$	A input to M register CLK	N/A	Yes	N/A	3.06/ –0.40	3.51/ –0.40	3.51/ –0.40	3.97/ –0.40	ns
$T_{DSPDCK\_B\_MREG}$/ $T_{DSPCKD\_B\_MREG}$	B input to M register CLK	Yes	Yes	N/A	3.96/ –0.68	4.58/ –0.68	4.58/ –0.68	7.00/ –0.68	ns
$T_{DSPDCK\_D\_MREG}$/ $T_{DSPCKD\_D\_MREG}$	D input to M register CLK	Yes	Yes	N/A	4.23/ –0.56	4.80/ –0.56	4.80/ –0.56	6.84/ –0.56	ns
$T_{DSPDCK\_OPMODE\_MREG}$/ $T_{DSPCKD\_OPMODE\_MREG}$	OPMODE to M register CLK	Yes	Yes	N/A	4.18/ –0.48	4.80/ –0.48	4.80/ –0.48	6.88/ –0.48	ns
		No	Yes	N/A	2.37/ –0.48	2.70/ –0.48	2.70/ –0.48	4.28/ –0.48	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock									
$T_{DSPDCK\_A\_PREG}$/ $T_{DSPCKD\_A\_PREG}$	A input to P register CLK	N/A	Yes	Yes	4.32/ –0.76	5.06/ –0.76	5.06/ –0.76	7.52/ –0.76	ns
$T_{DSPDCK\_B\_PREG}$/ $T_{DSPCKD\_B\_PREG}$	B input to P register CLK	Yes	Yes	Yes	5.87/ –0.59	6.87/ –0.59	6.87/ –0.59	10.55/ –0.59	ns
		No	Yes	Yes	4.14/ –0.93	4.68/ –0.93	4.68/ –0.93	8.12/ –0.93	ns
$T_{DSPDCK\_C\_PREG}$/ $T_{DSPCKD\_C\_PREG}$	C input to P register CLK	N/A	N/A	Yes	2.20/ –0.23	2.25/ –0.23	2.25/ –0.23	3.27/ –0.23	ns
$T_{DSPDCK\_D\_PREG}$/ $T_{DSPCKD\_D\_PREG}$	D input to P register CLK	Yes	Yes	Yes	5.90/ –0.92	6.91/ –0.92	6.91/ –0.92	10.39/ –0.92	ns

Table 65: **Global Clock Input to Output Delay With DCM in Source-Synchronous Mode**

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, *with* DCM in Source-Synchronous Mode.							
$T_{ICKOFDCM\_0}$	Global Clock and OUTFF *with* DCM	XC6SLX4	5.03	N/A	7.21	8.05	ns
		XC6SLX9	5.03	6.13	7.21	8.05	ns
		XC6SLX16	5.08	5.51	6.44	7.96	ns
		XC6SLX25	4.81	5.13	5.69	7.94	ns
		XC6SLX25T	4.81	5.13	5.69	N/A	ns
		XC6SLX45	5.26	5.69	6.63	7.92	ns
		XC6SLX45T	5.26	5.69	6.63	N/A	ns
		XC6SLX75	4.77	5.18	5.88	7.95	ns
		XC6SLX75T	4.77	5.18	5.88	N/A	ns
		XC6SLX100	4.72	5.11	5.76	8.59	ns
		XC6SLX100T	4.76	5.11	5.76	N/A	ns
		XC6SLX150	4.90	5.30	5.93	7.93	ns
		XC6SLX150T	4.90	5.30	5.93	N/A	ns
		XA6SLX4	5.35	N/A	7.21	N/A	ns
		XA6SLX9	5.35	N/A	7.21	N/A	ns
		XA6SLX16	5.42	N/A	6.44	N/A	ns
		XA6SLX25	5.13	N/A	5.69	N/A	ns
		XA6SLX25T	5.13	N/A	5.79	N/A	ns
		XA6SLX45	5.58	N/A	6.63	N/A	ns
		XA6SLX45T	5.58	N/A	6.63	N/A	ns
		XA6SLX75	5.09	N/A	5.87	N/A	ns
		XA6SLX75T	5.09	N/A	5.87	N/A	ns
		XA6SLX100	N/A	N/A	6.44	N/A	ns
		XQ6SLX75	N/A	N/A	5.87	7.95	ns
		XQ6SLX75T	5.09	N/A	5.87	N/A	ns
		XQ6SLX150	N/A	N/A	6.06	7.93	ns
		XQ6SLX150T	5.50	N/A	6.06	N/A	ns

Notes:
1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. DCM output jitter is already included in the timing calculation.

Table 71: **Global Clock Setup and Hold Without DCM or PLL (Default Delay)**

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.(1)							
T_{PSFD}/ T_{PHFD}	Default Delay(2) Global Clock and IFF(3) without DCM or PLL	XC6SLX4	0.66/1.17	N/A	1.05/0.79	2.09/1.05	ns
		XC6SLX9	0.66/1.17	0.75/1.17	1.05/1.17	2.09/1.05	ns
		XC6SLX16	0.87/1.16	0.93/1.16	0.96/1.16	1.86/1.06	ns
		XC6SLX25	0.68/0.77	0.81/0.81	0.87/0.82	2.21/1.33	ns
		XC6SLX25T	0.68/0.77	0.81/0.81	0.87/0.82	N/A	ns
		XC6SLX45	0.40/1.05	0.42/1.17	0.64/1.20	1.61/1.67	ns
		XC6SLX45T	0.40/1.05	0.42/1.17	0.64/1.20	N/A	ns
		XC6SLX75	0.41/1.11	0.41/1.13	0.80/1.14	1.23/1.82	ns
		XC6SLX75T	0.41/1.11	0.41/1.13	0.80/1.14	N/A	ns
		XC6SLX100	0.39/1.12	0.39/1.23	0.39/1.28	1.13/1.94	ns
		XC6SLX100T	0.39/1.12	0.39/1.23	0.39/1.28	N/A	ns
		XC6SLX150	0.23/1.54	0.23/1.62	0.23/1.62	1.14/2.05	ns
		XC6SLX150T	0.23/1.54	0.23/1.62	0.23/1.62	N/A	ns
		XA6SLX4	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX9	0.73/1.18	N/A	1.05/0.80	N/A	ns
		XA6SLX16	0.90/1.20	N/A	0.96/0.75	N/A	ns
		XA6SLX25	0.70/0.81	N/A	0.87/0.91	N/A	ns
		XA6SLX25T	0.76/0.81	N/A	1.03/0.91	N/A	ns
		XA6SLX45	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX45T	0.40/1.06	N/A	0.64/1.20	N/A	ns
		XA6SLX75	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XA6SLX100	N/A	N/A	0.86/1.55	N/A	ns
		XQ6SLX75	N/A	N/A	0.80/1.18	1.23/1.82	ns
		XQ6SLX75T	0.41/1.24	N/A	0.80/1.18	N/A	ns
		XQ6SLX150	N/A	N/A	0.28/1.57	1.14/2.05	ns
		XQ6SLX150T	0.28/1.78	N/A	0.28/1.57	N/A	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. Default delay uses IODELAY2 tap 0.
3. IFF = Input Flip-Flop or Latch.

Table 74: **Global Clock Setup and Hold With PLL in System-Synchronous Mode**

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard.(1)							
T_{PSPLL}/ T_{PHPLL}	No Delay Global Clock and IFF(2) with PLL in System-Synchronous Mode	XC6SLX4	1.37/0.25	N/A	1.52/0.41	2.07/0.69	ns
		XC6SLX9	1.37/0.21	1.48/0.21	1.52/0.26	2.07/0.69	ns
		XC6SLX16	1.33/–0.03	1.53/–0.02	1.60/–0.02	1.57/0.48	ns
		XC6SLX25	1.65/0.28	1.71/0.28	1.91/0.28	2.44/0.76	ns
		XC6SLX25T	1.65/0.28	1.71/0.28	1.91/0.28	N/A	ns
		XC6SLX45	1.55/0.18	1.64/0.18	1.75/0.18	2.02/0.90	ns
		XC6SLX45T	1.55/0.18	1.64/0.18	1.75/0.18	N/A	ns
		XC6SLX75	1.77/0.21	1.89/0.21	2.13/0.21	2.46/0.53	ns
		XC6SLX75T	1.77/0.21	1.89/0.21	2.13/0.21	N/A	ns
		XC6SLX100	1.44/0.32	1.52/0.32	1.70/0.32	1.78/0.86	ns
		XC6SLX100T	1.44/0.32	1.52/0.32	1.70/0.32	N/A	ns
		XC6SLX150	1.39/0.49	1.48/0.49	1.67/0.49	1.94/0.94	ns
		XC6SLX150T	1.39/0.49	1.48/0.49	1.67/0.49	N/A	ns
		XA6SLX4	1.61/0.10	N/A	1.64/0.28	N/A	ns
		XA6SLX9	1.61/0.10	N/A	1.64/0.28	N/A	ns
		XA6SLX16	1.89/–0.08	N/A	1.72/–0.08	N/A	ns
		XA6SLX25	1.85/0.16	N/A	2.08/0.16	N/A	ns
		XA6SLX25T	1.85/0.16	N/A	2.17/0.16	N/A	ns
		XA6SLX45	1.58/0.07	N/A	1.87/0.03	N/A	ns
		XA6SLX45T	1.58/0.07	N/A	1.87/0.03	N/A	ns
		XA6SLX75	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XA6SLX75T	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XA6SLX100	N/A	N/A	2.34/0.14	N/A	ns
		XQ6SLX75	N/A	N/A	2.25/0.06	2.46/0.53	ns
		XQ6SLX75T	1.80/0.06	N/A	2.25/0.06	N/A	ns
		XQ6SLX150	N/A	N/A	1.79/0.37	1.94/0.94	ns
		XQ6SLX150T	1.43/0.37	N/A	1.79/0.37	N/A	ns

Notes:
1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage. These measurements include PLL CLKOUT0 jitter.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 79: **Package Skew *(Cont'd)***

Symbol	Description	Device	Package[2]	Value	Units
$T_{PKGSKEW}$	Package Skew[1]	LX45	CSG324	70	ps
			CS(G)484	99	ps
			FG(G)484	109	ps
			FG(G)676	138	ps
		LX45T	CSG324	75	ps
			CS(G)484	100	ps
			FG(G)484	95	ps
		LX75	CS(G)484	101	ps
			FG(G)484	107	ps
			FG(G)676	161	ps
		LX75T	CS(G)484	107	ps
			FG(G)484	110	ps
			FG(G)676	134	ps
		LX100	CS(G)484	95	ps
			FG(G)484	155	ps
			FG(G)676	144	ps
		LX100T	CS(G)484	88	ps
			FG(G)484	111	ps
			FG(G)676	147	ps
			FG(G)900	134	ps
		LX150	CS(G)484	84	ps
			FG(G)484	103	ps
			FG(G)676	115	ps
			FG(G)900	121	ps
		LX150T	CS(G)484	83	ps
			FG(G)484	88	ps
			FG(G)676	141	ps
			FG(G)900	120	ps

Notes:
1. These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from Pad to Ball.
2. Some of the devices are available in both Pb and Pb-free (additional G) packages as standard ordering options. See DS160: *Spartan-6 Family Overview* for more information.

Table 80: **Sample Window**

Symbol	Description	Device[1]	Speed Grade				Units
			-3	-3N	-2	-1L	
T_{SAMP}	Sampling Error at Receiver Pins[2]	All	510	510	530	740	ps
T_{SAMP_BUFIO2}	Sampling Error at Receiver Pins using BUFIO2[3]	All	430	430	450	590	ps

Notes:
1. LXT devices are not available with a -1L speed grade.
2. This parameter indicates the total sampling error of Spartan-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the DCM to capture the DDR input registers' edges of operation. These measurements include:
   - CLK0 DCM jitter
   - DCM accuracy (phase offset)
   - DCM phase shift resolution

   These measurements do not include package or clock tree skew.
3. This parameter indicates the total sampling error of Spartan-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO2 clock network and IODELAY2 to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 81: **Source-Synchronous Pin-to-Pin Setup/Hold and Clock-to-Out Using BUFIO2**

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO2							
T_{PSCS}/T_{PHCS}	IFF setup/hold using BUFIO2 clock	XC6SLX4	0.57/0.94	N/A	0.95/1.12	0.27/1.56	ns
		XC6SLX9	0.40/0.95	0.50/0.96	0.60/1.12	0.27/1.56	ns
		XC6SLX16	0.48/0.74	0.55/0.75	0.69/0.83	1.27/1.31	ns
		XC6SLX25	0.28/1.02	0.28/1.12	0.28/1.24	0.15/1.78	ns
		XC6SLX25T	0.28/1.02	0.28/1.12	0.28/1.24	N/A	ns
		XC6SLX45	0.42/1.19	0.44/1.29	0.50/1.40	0.12/1.83	ns
		XC6SLX45T	0.42/1.19	0.44/1.29	0.50/1.40	N/A	ns
		XC6SLX75	0.38/1.48	0.38/1.63	0.38/1.84	0.05/2.78	ns
		XC6SLX75T	0.38/1.48	0.38/1.63	0.38/1.84	N/A	ns
		XC6SLX100	0.06/1.48	0.06/1.63	0.06/1.87	–0.03/2.72	ns
		XC6SLX100T	0.06/1.48	0.06/1.63	0.06/1.87	N/A	ns
		XC6SLX150	0.04/1.73	0.04/1.75	0.04/1.98	–0.08/3.07	ns
		XC6SLX150T	0.04/1.73	0.04/1.75	0.04/1.98	N/A	ns
		XA6SLX4	0.64/0.96	N/A	0.97/1.12	N/A	ns
		XA6SLX9	0.44/0.99	N/A	0.62/1.16	N/A	ns
		XA6SLX16	0.50/0.78	N/A	0.69/0.83	N/A	ns
		XA6SLX25	0.28/1.04	N/A	0.28/1.25	N/A	ns
		XA6SLX25T	0.28/1.04	N/A	0.28/1.25	N/A	ns
		XA6SLX45	0.43/1.21	N/A	0.50/1.40	N/A	ns
		XA6SLX45T	0.43/1.21	N/A	0.50/1.40	N/A	ns
		XA6SLX75	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XA6SLX75T	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XA6SLX100	N/A	N/A	1.01/1.63	N/A	ns
		XQ6SLX75	N/A	N/A	0.38/1.84	0.05/2.78	ns
		XQ6SLX75T	0.38/1.49	N/A	0.38/1.84	N/A	ns
		XQ6SLX150	N/A	N/A	0.04/1.98	–0.08/3.07	ns
		XQ6SLX150T	0.04/1.75	N/A	0.04/1.98	N/A	ns